

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 277944US28X PCT		SERIAL NO. 10/519,169	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Takashi KIKUKAWA, et al.			
				FILING DATE December 20, 2004		GROUP 1794	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
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	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
/G.H./	AM	2002-109786	04/12/02	JP (with English abstract)		NO	
	AN	06-262854	09/20/94	JP (with English abstract)		NO	
	AO	2000-353341	12/19/00	JP (with English abstract)		NO	
	AP	2002-269827	09/20/02	JP (with English abstract)		NO	
	AQ	2002-298439	10/11/02	JP (with English abstract)		NO	
	AR	07-210874	08/11/95	JP (with English abstract)		NO	
	AS	05-028535	02/05/93	JP (with English abstract)		NO	
	AT	05-242524	09/21/93	JP (with English abstract)		NO	
	AU	06-290486	10/18/94	JP (with English abstract)		NO	
/G.H./	AV	05-028498	02/05/93	JP (with English abstract)		NO	
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
/G.H./	AW	FUJI et al. "A Near-Field Recording and Readout Technology Using a Metallic Probe in an Optical Disk", Jpn. J. Appl. Phys., vol. 39, part 1, no. 2B, pages 980-981 2000					
	AX						
	AY						
	AZ						<input type="checkbox"/> Additional References sheet(s) attached
Examiner /Gerard Higgins/					Date Considered 01/29/2008		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							



LIST OF RELATED CASES CITED BY APPLICANT UNDER 37 CFR 1.56	Docket No.: 277944US28X PCT	Serial No.: 10/519,169
	Inventor: Takashi KIKUKAWA, et al.	
	Filing Date: December 20, 2004	Group: 1794

LIST OF RELATED CASES

<u>Examiner Initial</u>	<u>Docket No.</u>	<u>Serial or Patent Number</u>	<u>Filing or Issue Date</u>	<u>Patent App. Publication No.</u>	<u>Inventor or Applicant</u>
/G.H./	283988US0PCT	10/563,012	12/30/05		KIKUKAWA, et al.
/G.H./	283989US0PCT	10/562,901	12/30/05		KIKUKAWA, et al.
see below	277944US28XPCT*	10/519,169	12/20/04		KIKUKAWA, et al.

Examiner /Gerard Higgins/

Date Considered

01/29/2008

*Present Application; listed for information
NFO/sbc ok



SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 277944US28X PCT		SERIAL NO. 10/519,169	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Takashi KIKUKAWA, et al.			
				FILING DATE September 16, 2005		GROUP 1794	
				2020			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
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	AP						
	AQ						
	AR						
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	AT						
	AU						
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
/G.H./	AW	Junji TOMINAGA, et al., "THE CHARACTERISTICS AND THE POTENTIAL OF SUPER RESOLUTION NEAR-FIELD STRUCTURE", JAPANESE JOURNAL OF APPLIED PHYSICS, XP 002451221, Vol. 39, No. 2B, February 2000, Pages 957-961					
/G.H./	AX	Marcell PEUCKERT, "XPS STUDY ON SURFACE AND BULK PALLADIUM OXIDE, ITS THERMAL STABILITY, AND A COMPARISON WITH OTHER NOBLE METAL OXIDES", JOURNAL OF PHYSICAL CHEMISTRY, XP 002451222, Vol. 89, 1985, Pages 2481-2486					
/G.H./	AY	Takashi KIKUKAWA, et al., "RECORDING AND READOUT MECHANISMS OF SUPER-RESOLUTION NEAR-FIELD STRUCTURE DISC WITH SILVER-OXIDE LAYER", JAPANESE JOURNAL OF APPLIED PHYSICS, XP 002452548, Vol. 42, No. 2B, February 2003, Pages 1038 and 1039					
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner /Gerard Higgins/					Date Considered 01/29/2008		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							